Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/541,384	TAKEI ET AL.	
Examiner	Art Unit	
Nam Huynh	2617	

	SEAR	CHED	
Class	Subclass	Date	Examiner
455	412.2	9/20/2006	NTH
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See EAST search notes.	9/20/2006	NTH		